

ABSTRACT OF THE DISCLOSURE

1 An integrated emission microscope with an emitted
2 radiation detection system for collecting and analyzing
3 radiation from a device under test. A semi-ellipsoidal
4 mirror of high ellipticity directs emitted radiation
5 from the device under test through an aperture to a
6 radiation guide, which transmits the radiation to
7 spectral analyzer. The device under test may be mounted
8 on a scanning stage. The system permits high spatial
9 resolution selected area spectroscopic analysis,
10 panchromatic imaging, and spectroscopic mapping of the
11 emitted radiation from the device under test.